

X-MET[®] for mining

Fast, on-site ore analysis!

Highly accurate and repeatable sample analysis

At the pull of a trigger, Oxford Instruments' hand-held **X-MET5000** and **X-MET5100** X-ray fluorescence (XRF) analyzers deliver fast, highly accurate on-site sample screening and analysis.

Both analysers provide real-time data in seconds, for:

- Ore exploration
- On-site excavation control
- Mine mapping
- Process monitoring: concentrates, tailings etc.
- Environmental control

What's more, **X-MET** enables precise portable GPS integration for real-time ore exploration and mine mapping.

Rapid single shot mine mapping!

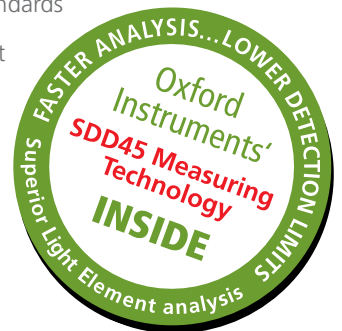


Minimal need for expensive and time consuming laboratory analysis

- Highly accurate ore analysis from Al to U
- Reliable Al, Si, P, S analysis without vacuum or helium attachments
- Measure directly on drill core sample
- Certified IP54 NEMA 3 splash and dust proof
- Results obtained in seconds
- Optional easy-to-use software for unbeatable accuracy
- Universal Fundamental Parameter analysis mode for measurement of ores without known standards
- Go/No-Go user configurable result format
- User interface in >10 languages
- Rapid data transfer to PC

Silicon Drift Detector technology improves productivity!

Top of the range **X-MET5100** combines Oxford Instruments' groundbreaking Silicon Drift Detector (SDD) with a powerful 45kV X-ray tube. This cutting edge technology delivers a five times faster measurement speed, much better detection limits and significant accuracy improvement over conventional systems. Isn't it time you used **X-MET** to improve your productivity and screening confidence?



The Business of Science[®]



Rugged and reliable tool for fast analysis

- Withstands all weather conditions and rough treatment
- IP54 (NEMA 3) approved. Superior dust and moisture protection
- High-strength environmentally sealed housing
- Long battery operating time, charge indicator on battery and user interface

High performance

- Single-shot analysis of all important elements in ore exploration: Fe, Cu, Cr, Zn, Pb, Mn, Ni, Co, Mo, Ta, W etc.
- Al, Si, P, S analysis of prepared samples. No need for vacuum or He attachments! (**X-MET5100**)
- Advanced automatic matrix correction
- Rapid analysis with typical measurement times of 10 – 30 seconds (**X-MET5000**) or 2 – 5 seconds (**X-MET5100**) depending on the elements of interest and required precision
- Low detection limits, **X-MET5000** can typically detect 5 – 30 ppm concentration with 120s measuring time. **X-MET5100** detection limits are even lower and ppm level analysis can be done in just 10 – 30 seconds
- High speed automatic averaging – calculate averages of 2 – 50 measurements and save both individual results and average results in a log file

Splash and dust proof cover



Choice of analysis modes

- **Fundamental Parameter Calculations when standards are not available**
 - 30 elements between Al-U (**X-MET5100**) and between K-U (**X-MET5000**)
 - Suitable for wide range of ore types
- **Empirical Calibration available for optimized accuracy**
 - Create custom calibrations on-site with optional PC software package

Sample measurement is fast and simple

- Direct on-site surface measurement for quick pre-screening without sample preparation
- Laboratory grade analysis from a plastic bag or sample cup in bench-top mode

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